Sheet 1 of 2 Form PTO-1449 Atty Docket No. Serial No. U.S. Department of Commerce, Patent and Trademark Office BDG005 10/042,812 INFORMATION DISCLOSURE STATEMENT Applicant (Use several sheets if necessary) Cheng-Lien Chiang Filing Date Group Art Unit January 9, 2002 U.S. Patent Documents *Examiner Document Filing Date Initial Number Date Name Class Subclass If Appropriate C. C. AA 5,081,520 01/1992 Yoshii et al. 357 80 Mullen, III et al. (. C 5,241,133 08/1993 52.4 174 (. l. 5,394,303 02/28/95 749 AC Yamaji 361 C, C_{\perp} AD 5,665,652 09/1997 Shimizu 438 127 (C, C)ΑE 5,674,785 10/1997 Akram et al. 437 217 AF 5,744,827 04/28/98 Jeong et al. 257 686 AG 5,744,859 04/1998 Ouchida 257 668 09/1998 5,804,771 AΗ McMahon et al. 174 255 ΑI 5,811,879 09/1998 Akram 257 723 ΑJ 5,949,655 09/1999 Glenn 783 361 C.C.AΚ 6,013,877 01/2000 174 264 Degani et al. C. C. ΑL 6,143,588 11/2000 Glenn 438 116 C.C. 6,159,770 12/2000 AM Tetaka et al. 438 112 C. C. 6,274,927 08/2001 AN Glenn 257 680 Other Art (Including Author, Title, Date, Pertinent Pages, Etc.) AO Crowley, "Socket Developments for CSP and FBGA Packages," Chip Scale Review, C. C. May 1998, pp. 37-40. Forster, "Socket Challenges for Chip-Scale Packages," Chip Scale Review, May C_{C} 1998, pp. 43-47. Amagai, "Chip-Scale Packages for Center-Pad Memory Devices," Chip Scale C. C ΑQ Review, May 1998, pp. 68-77. AR Vandevelde et al., "The PSGA, a Lead-Free CSP for High Performance & High Reliable Packaging," Proceedings of the 2001 International Symposium on Microelectronics, October 9, 2001, pp. 260-265. Examiner Date Considered 4/17/03

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with your next communication to Applicant.

				Sheet 2 of 2
Form PTO-1449			Atty Docket No.	Serial No.
U.S. Department of Commence Patent and Trademark Office			BDG005	10/042,812
I	NFORM	MATION DISCLOSURE STATEMENT	Applicant	
(Use several sheets if necessary)			Cheng-Lien Chiang	
			Filing Date	Group Art Unit
	r		January 9, 2002	
*Examiner Initial		Other Art (Including Author, Title, Date, Pertinent Pages, Etc.)		
: C. c.	AA	U.S. Application Serial No. 09/865,367, filed May 24, 2001, entitled "Semiconductor Chip Assembly With Simultaneously Electroplated Contact Terminal and Connection Joint"		
C. C.	AB	U.S. Application Serial No. 09/864,555, filed May 24, 2001, entitled "Semiconductor Chip Assembly with Simultaneously Electrolessly Plated Contact Terminal and Connection Joint"		
(, (,	AC	U.S. Application Serial No. 09/864,773, filed May 24, 2001, entitled "Semiconductor Chip Assembly With Ball Bond Connection Joint"		
(AD	U.S. Application Serial No. 09/878,649 filed June 11, 2001, entitled "Method of Making a Semiconductor Chip Assembly with a Conductive Trace Subtractively Formed Before and After Chip Attachment"		
(.(.	AE	U.S. Application Serial No. 09/878,626 filed June 11, 2001, entitled "Method of Connecting a Conductive Trace to a Semiconductor Chip"		
C.C.	AF	U.S. Application Serial No. 09/917,339 filed July 27, 2001, entitled "Method of Connecting a Bumped Compliant Conductive Trace to a Semiconductor Chip"		
C.C.	AG	U.S. Application Serial No. 09/927,216 filed August 10, 2001, entitled "Semiconductor Chip Assembly with Hardened Connection Joint"		
C.C.	АН	U.S. Application Serial No. 09/939,140 filed August 24, 2001, entitled "Semiconductor Chip Assembly with Interlocked Conductive Trace"		
C.C.	AI	U.S. Application Serial No. 09/962,754 filed September 24, 2001, entitled "Method of Connecting a Conductive Trace and an Insulative Base to a Semiconductor Chip"		
C. C.	AJ	U.S. Application Serial No. 09/972,796 filed October 6, 2001, entitled "Method of Connecting a Bumped Compliant Conductive Trace and an Insulative Base to a Semiconductor Chip"		
C.C.	AK	U.S. Application Serial No. 09/997,973 filed November 29, 2001, entitled "Method of Connecting a Bumped Conductive Trace to a Semiconductor Chip"		
Examiner Colonia	Ad	Date Considered 4/17	1/03	

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